

AMENDMENTS TO THE CLAIMS

Please add or amend the claims to read as follows, and cancel without prejudice or disclaimer to resubmission in a divisional or continuation application claims indicated as cancelled:

1. (Currently amended) ~~An apparatus~~ Apparatus for the processing of a sectional image (I) that is reconstructed from X-ray projections of an object from different directions, the apparatus being adapted ~~programmed~~ to execute the following steps: a) segmenting at least one segmented area from the sectional image, where the reconstructed X-ray density within said at least one segmented area lies within a given density interval; determination b) determining of a baseline function (B) that describes spatially slowly varying artifacts of the sectional image (I) based on the data of said at least one segmented area; b) c) calculating a corrected image (I*) by compensating the original sectional image (I) with the help of said baseline function (B).
2. (Currently amended) ~~An apparatus~~ Apparatus according to claim 1, ~~characterised in that wherein~~ the sectional image (I) represents a three-dimensional volume, and ~~that the~~ corresponding three-dimensional baseline function (B) is composed of separate two-dimensional baseline functions that are calculated for two-dimensional slices of the sectional image (I).
3. (Cancelled)
4. (Currently amended) ~~An apparatus~~ Apparatus according to claim 3-1, ~~characterised in that wherein~~ the baseline function (B) is determined by fitting a parametric model function to the data in the segmented areas (M).
5. (Currently amended) ~~An apparatus~~ Apparatus according to claim 4, ~~characterised in that wherein~~ the parametric model function is a spline function and/or a polynomial, preferably a polynomial of sixth degree.

6. (Currently amended) An apparatus ~~Apparatus~~ according to claim 3 1, characterised in that wherein the baseline function is determined by low-pass filtering of the data in the segmented areas ~~(M)~~.
7. (Currently amended) An apparatus ~~Apparatus~~ according to claim 1, characterised in that wherein the baseline function is determined by a) spectral analysis of the sectional image ~~(I)~~ or the segmented areas ~~(M)~~ of the sectional image; b) composition of the baseline function from only the lower frequency components of the resulting spectrum.
8. (Currently amended) An apparatus ~~Apparatus~~ according to claim 1, characterised in that wherein image areas outside the object are segmented and excluded from the correction with the baseline function ~~(B)~~.
9. (Currently amended) An apparatus ~~Apparatus~~ according to claim 1, characterised in that it ~~comprises~~ comprising a rotational cone beam X-ray device for the generation of X-ray projections of an object.
10. (Currently amended) A method ~~Method~~ for the processing of a sectional image ~~(I)~~ that is reconstructed from X-ray projections of an object from different directions, ~~comprising the following steps~~ the method comprising: a) segmenting at least one segmented area from the sectional image, where the reconstructed X-ray density within said at least one segmented area lies within a given density interval; -a) b) ~~determination determining~~ of a baseline function ~~(B)~~ that describes spatially slowly varying artifacts of the sectional image ~~(I)~~ based on the data of said at least one segmented area; b) c) calculating a corrected image ~~(I[±])~~ by compensating the original sectional image ~~(I)~~ with the help of said baseline function ~~(B)~~.